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[US/US]; 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).

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(74) Common Representative: **KONINKLIJKE PHILIPS ELECTRONICS N.V.**; c/o Shannon Lester, 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).

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(71) Applicant (for all designated States except US): **KONINKLIJKE PHILIPS ELECTRONICS N.V.** [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).

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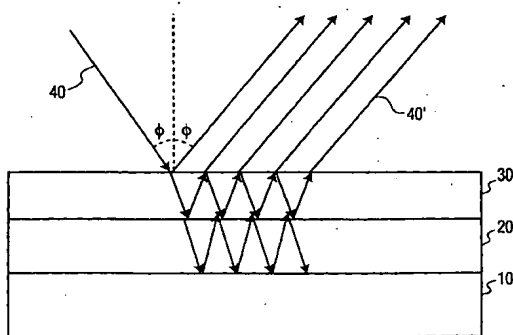
(72) Inventor; and

(75) Inventor/Applicant (for US only): **ZIGER, David**

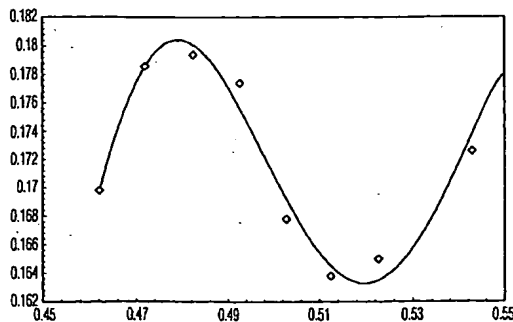
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(54) Title: METHOD FOR DETERMINING OPTIMAL RESIST THICKNESS



A



B

(57) Abstract: In an example embodiment, there is a method (600) for determining an approximately optimal resist thickness comprising providing a first substrate coated with a resist film having a first thickness using a first coat program (605, 610). The first thickness of resist is measured (615, 620). A second substrate is provided (625) and coated with a resist film using the first coat program. The resist film on the second substrate is exposed to radiation. The reflectance spectrum near the actinic wavelength of the resist film is measured (630). As a function of the periodicity of the reflectance spectrum, an effective refractive index is determined. Based on the effective refractive index, a periodicity of a swing curve of the resist film coated on the second substrate is determined (635). The maxima and minima are determined as a function of the periodicity.



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